

<b>Notice of References Cited</b>	Application/Control No. 09/912,558		Applicant(s)/Patent Under Reexamination WEIMER ET AL.	
	Examiner Erik Kielin		Art Unit 2813	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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X	C	US-6,136,728 A	10-2000	Wang, Xiewen	438/773
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NON-PATENT DOCUMENTS

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	U	Van Zant, Microchip Fabrication, 4th ed. McGraw-Hill: New York, 2000, pp. 163-164.
	V	Van Zant, Microchip Fabrication, A Practical Guide to Semiconductor Processing, 3rd ed. McGraw-Hill: New York, 1997, pp. 157-160.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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